



# Role of Ultrafast Charge Dynamics in Photocatalytic Water Oxidation

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## Water Oxidation Catalysts: Transition Metal Oxides $4h^+ + 2H_2O \longrightarrow O_2 + 4H^+ = E_0 = 0.6 V vs. Ag/AgCl$

Hydroxilated Surfaces α-Fe<sub>2</sub>O<sub>3</sub>(0001)

Bluhm, Salmeron, Nilsson *et. al.,* J. Phys. Chem. C (2010)

**Robust Catalysis** 



- Efficient and Sustainable Catalysis on TM Oxide Surfaces
- Hydroxilated surfaces common to TM Oxide Surfaces

### Heterogeneous Catalysis



Suggested First Hole Transfer (t=0):  $[h+] + [OH^{-}] \longrightarrow [OH^{*}]$ 

**Activation Barrier thru Transient Spectroscopy** 

# Challenges in Applying Ultrafast Spectroscopy to Catalysis

- Interplay of recombination and interfacial charge transfer
- Sensitivity to the surface
- Studying hetero-junctions (solid-solid, solid-liquid)
- Multi-electron transfer processes and "clocking" the cycle



# Catalysts & Devices Under Investigation



## Photo-electrochemistry of n-SrTiO<sub>3</sub>

High Quantum Efficiency with 1 kHz Laser (W  $\sim \alpha$ )



- Single 150 fs Pulse Triggers Multi-electron Transfer Water Oxidation
- Achieve high quantum efficiency (75%) under laser excitation

# Transient Reflectance of n-SrTiO<sub>3</sub>

Pump Band Gap, Probe Holes



Experimental conditions needed to probe k<sub>CT</sub>, [h]:

 $W = \alpha_{PUMP} = \alpha_{PROBE}$ 

#### Surface Sensitivity Thru Reflectivity



Width of Electric Field at High Q.E.: W ~ 25 nm

Pump Band Gap (300 nm, 4 eV):  $\alpha = \lambda/4\pi k \sim 24 \text{ nm}$ 

Probe Hole Absorption (800 nm, 1.5 eV):  $\alpha_{\text{REFL}} = \lambda/4\pi n \sim 27 \text{ nm}$ 

## Interfacial Charge Transfer



Change in kinetics reflects k<sub>cr</sub>, [h]



### Manipulating Interfacial Charge Transfer

SrNb<sub>0.001</sub>TiO<sub>3</sub> (0.1%)



- Interfacial charge transfer rate increases with increasing oxidative voltages
- Rate changes while current and quantum efficiency constant



- Kinetics are fit to a single exponential at early time scales
- Rate constant depends exponentially on applied V (Arrhenius Law)

M. Waegele, X. Chen, D. Herlihy, T. Cuk, JACS 2014

Voltage Distribution at the Surface



- Since the solution potential is invariant, changes in U<sub>H</sub> are tied to changes in the valence band edge potential,  $\phi_{\rm RE}$
- Changes in U<sub>H</sub> (Helmholtz Voltage) by applied U determined by capacitances at n-type SC/liquid interface

U<sub>H</sub>(V): Changing Surface Hole Potential

- (1)  $U + U_{FB} = U_{H} + U_{SC}$
- (2)  $U_{H} = (q_{sc} + q_{photo}) / C_{H}$

 $U_{\rm H}(0) = 0.65 \text{ V give } C_{\rm H} = 21 \text{ uF/cm}^2$ 





Activation Barrier of First Hole Transfer



Quantifies barrier to localizing VB hole onto a molecular O2p bond

## Conclusions

- Quantified interfacial charge transfer at n-type semiconductor/liquid interface
- Activation barrier (α, k<sub>0</sub>) for first hole transfer of water oxidation reaction in n-SrTiO<sub>3</sub>



- Next step on n-SrTiO<sub>3</sub>: concomitant intermediates using ultrafast infrared spectroscopy
- Investigate lower over-potential catalysts, and other ntype semiconductors stable in aqueous solutions (e.g. GaN)

## Acknowledgements

#### **Graduate Students**

Hoang Doan Stephanie Choing Kevin Pollack David Herlihy Xihan Chen Jonathon Radberg Aayush Singh (Undergraduate) Joseph Mosley (Volunteer)

### Postdoc

Matthias Waegele

### **Facilities**/Discussions

Heinz Frei Steve Leone Gabor Somorjai Eli Yablonovitch Ian Sharp (JCAP) Joel Ager (JCAP) Michelle Chang



Funding



AFOSR Young Investigator (Co<sub>3</sub>O<sub>4</sub>)

### Possible Intermediate Species Formed $k_1 \qquad k_1''$ $[h+]+[OH^-] \rightarrow [OH^*] \rightarrow [-OOH \text{ or }-OOTi]$

- -OOH is a likely intermediate: ms-FTIR (Frei)
- Single rate constant (k<sub>1</sub>) implies a highly populated –OOH surface?
- Probe nature of OH\* (or O\*) as surface trap (transient XAS)



### Ultrafast Transient IRRAS



- Small molecule rotations/bindings (-SCN, -NCS)
- Reaction Intermediate Rise Times
- Effects of surface potential/electric field vs. charge transfer

# **Transient Grating Diffraction**



 $\Delta I/I = R(t)\cos(\phi(t)) + TG(t)\cos[\Psi - \phi(t)]$ 

**Recombination (t)** =  $R(t)cos(\phi(t))$ 

**Diffusion (t)** =  $\varepsilon$  (t) = TG(t)/R(t) = exp (-Dq<sup>2</sup>/t)

Heterodyne Detection: **TG(t)**, **R(t)**,  $\phi$  (t) determined by varying  $\Psi$ , probe-ref phase



# Catalysts & Devices Under Investigation





# Transient Reflectivity on Hetero-junctions



- Charge separation spatially separated from hole injection into catalyst
- Ultrafast charge injection (~ 10 ps) unimpeded by slow diffusion kinetics
- Can recombination kinetics in GaAs & hole kinetics in Co<sub>3</sub>O<sub>4</sub> be separated in a transient reflectivity experiment?

## Kinetics of Holes in Catalyst Over-layer



- Surface sensitivity of ΔR w/ 400 nm probe
- Strong signal of surface holes with catalyst
- Time delay for hole injection (~10 ps)

- Kinetics vary w/ catalyst type
- Also with deposition technique
- Reproducibility for same batch



- 0.8 THz (& w/ 0.4 THz) signal generated from catalyst over-layer, independent of catalyst type
- Strength and decay of THz signal depends on catalyst type and deposition technique
- Potentially, mobile holes responding to THz in GaAs that decay to surface trapped states



Plasma frequency of p-dopants responding to  $\Delta E$  field

#### **THz Antenna**



**Effects of Electrolyte?** 

Free Carriers Injected in Catalyst Responding to THz field

## Conclusions

- Activation barrier (α, k<sub>0</sub>) for first hole transfer of water oxidation reaction in n-SrTiO<sub>3</sub>
- Next steps n-SrTiO<sub>3</sub>: (1) concomitant intermediates using ultrafast infrared spectroscopy, (2) transient diffraction gratings for interfacial hole diffusion
- Ultrafast photodiode for low over-potential catalysts: dynamics of charge-separated carriers at electrolyte interfaces

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### Reaction via surface hole (valance band oxygen)









(3)

Reaction via hot hole (surface axial oxygen)



Number of surface site calculation





- 1. SrTiO3 has a lattice constant of a=3.905A
- 2. (1,0,0) surface for SrTiO3 is cubic, which looks like the graph on the right
- 3. Each (1,0,0) lattice has 3 surface atoms(1 Ti, 2 O)
- 4. Therefore, each lattice has area of  $A=a^2=1.525*10^{-15}$  cm<sup>2</sup>
- Surface atom density=# of atoms on one lattice surface/lattice surface area
  So, surface atom density= 3/1.525\*10^-15cm<sup>2</sup> = 1.967\*10^15 atoms/cm<sup>2</sup>

### Voltage Distribution (Dark, Equilibrium)



- Photo-voltage at open circuit roughly half of U<sub>FB</sub>
- U<sub>H</sub>= 0.65 V in the dark, at equilibrium (no applied U)

### Voltage Distribution (Illumination)

Capacitance **Illuminated Junction** 3  $+ q_{sc}$ **q**<sub>photo</sub> Dark C (F/cm<sup>2</sup>) x 10<sup>-3</sup> 0.01 mJ/cm<sup>2</sup> +CB 0.04 mJ/cm<sup>2</sup> + ++ ++VB + p-type+ n-type 0 Reverse Forward Double Bias -1.5 -1.0 -0.5 **Bias** Layer V (vs. Ag/AgCl) Turner, Nozik APL **37** (1980)

• Photo-induced holes at interface create an interfacial p-type layer

• This interfacial "carrier inversion" changes U<sub>H</sub>, even with no applied U

#### SEM images a)-d) show damage on 0.1% Nb doped SrTiO3 under laser and applied bias condition



- ) Damaged sample at 1500× magnification
- b) Damaged sample at 1500× magnification
- b) Damaged sample at  $3500 \times$  magnification
- l) Undamaged sample at 1500× magnification

- 1. SEM image shows laser burned holes on sample surface, most of the holes have 5um as diameter while some big holes have 10um as diameter
- 2. No damage is observed if only laser is applied to our sample, damage happens when current is running through the sample and laser is applied.
- 3. Laser spot size is 500um(FWHM) but the peak is narrow around 10um
- 4. One possible mechanism for the damage is coulomb explosion where high density of excitons generated by laser accumulate at sample surface causes explosion

# Water Oxidation & Over-Potential



**Reaction Coordinate** 

How do the surface dynamics modify the kinetic barriers and thermodynamics of each intermediate in the cycle?